Application/Control No. O9/686,572 Examiner Nhon (Gary) D Nguyen Applicant(s)/Patent Under Reexamination DUBIL ET AL. Art Unit Page 1 of 1

Notice of References Cited

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6466233 B1	10-2002	Mitani, Hitoshi	345/716
	В	US-6431875 B1	08-2002	Elliott, Kevin et al.	434/322
	С	US-6466971 B1	10-2002	Humpleman, Richard et al.	709/220
	D	US-6446192 B1	09-2002	Narasimhan, Subram et al.	712/29
	E	US-6374296 B1	04-2002	Lim, Hoon Chiat et al.	709/225
	F	US-			
	G	US-			
	H	US-			
	ı	US-			
	J	US-			
	к	US-			
	L	US-		· · · · · · · · · · · · · · · · · · ·	
	М	US-			

FOREIGN PATENT DOCUMENTS

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	Р					
	Q					
	R					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.